



BOX AF
EXPEDITED PROCEDURE
EXAMINING GROUP 2811

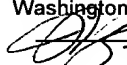
RECEIVED
#76/E
4/17/01

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)
Shunpei YAMAZAKI) Group Art Unit: 2811
Serial No. 09/334,646) Examiner: S. HU
Filed: June 17, 1999)
For: SEMICONDUCTOR DEVICE AND)
FABRICATION METHOD THEREOF)

AMENDMENT

Commissioner for Patents
Washington, D.C. 20231

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to: Commissioner for Patents, Washington, D.C. 20231, on 04/11/01

Wendy K. Spradlin

Sir:

Responsive to the Office Action of **December 11, 2000**, the period for response having been extended two (2) months until April 11, 2001, the following amendment and remarks are respectfully submitted in connection with the above-identified application.

IN THE SPECIFICATION:

Please amend the specification as follows:

On page 7, replace the second full paragraph with the following:

Figure 5 shows plots of the relationship between the full-width at half maximum for the Raman spectrum and the energy density of the laser light irradiation for samples heated to different temperatures. The full-width at half maximum shown on the vertical axis is a parameter indicating the ratio (W/W_0) between the width W_0 of the spectrum at a position at half of the Raman spectrum intensity for a monocrystalline silicon wafer and the width W of the spectrum at a position at half of the Raman spectrum intensity which was actually obtained for the sample. W and W_0 are defined as the width of the spectrum at a position of half of the Raman spectrum intensity, as shown in Figure 7. In general, a narrow, sharp Raman spectrum means that the crystallinity is excellent. Consequently, in general the width of the Raman spectrum for monocrystalline silicon is the thinnest and the sharpest. It should be noted that the samples which were used were the same as those for which the data shown